

FORM PTO-1449

INFORMATION DISCLOSURE CITATION IN AN APPLICATION

{Use several sheets if necessary}

ATTY DOCKET NO. 0171-0822P	APPLICATION NO. NEW
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APPLICANT
OHBA, Toshio et al.

FILING DATE
February 20, 2002

U. S. PATENT DOCUMENTS

FOREIGN PATENT DOCUMENTS

OTHER DOCUMENTS

OTHER DOCUMENTS (include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.)

MURATA, Kenji et al., "Monte Carlo Calculations on Electron Scattering in a Solid Target" Japanese Journal of Applied Physics, VOL. 10, NO. 6, June 1971, pgs. 678-686.

SHIMIZU, Ryuichi et al., "The Monte Carlo technique as applied to the fundamentals of EPMA and SEM" J. Appl. Phys., VOL. 43, NO. 10, October 1972, pgs. 4233-4249.

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PANDEY L.N., "A comparative study of electron transport phenomenon in the keV range", J. Appl. Phys., VOL. 66, NO. 12, December 1989, pgs. 6059-6064.

EXAMINER

David Herring

DATE CONSIDERED

08/05/04

08/05/04

REMARKS: Initial if citation considered whether or not citation is in conformance with N.P.E.P. 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Renforcement

Form PTO-1449		ATTY DOCKET NO. 0171-0822P	APPLICATION NO. 10/077,975			
INFORMATION DISCLOSURE CITATION IN AN APPLICATION <small>(Use several sheets if necessary)</small>		APPLICANT Toshio OHBA et al.				
		FILING DATE February 20, 2002	GROUP Unassigned			
U.S. PATENT DOCUMENTS						
EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
<i>RLH</i>	5,219,623	1993-06-15	Petisce	—	—	<i>RECEIVED</i>
<i>RLH</i>	5,217,518	1993-06-08	Petisce	—	—	<i>AUG 07 2002</i>
						<i>TC 1/00</i>
FOREIGN PATENT DOCUMENTS						
EXAMINER INITIAL	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB CLASS	TRANSLATION
						YES
<i>RLH</i>	0 445 980 A2	1991-09-11	EP	—	—	
<i>RLH</i>	62 162 655	1987-07-18	JP (W/ABSTRACT)	—	—	X
<i>RLH</i>	97/37951	1997-10-16	WO	—	—	
OTHER DOCUMENTS <small>(Include Name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.)</small>						
EXAMINER	<i>RLH</i>					
	DATE CONSIDERED <i>08/05/04</i>					
<small>EXAMINER: Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</small>						

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